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APPLICANTS

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\*\* CONTINUING DATA \*\*\*\*\* *None*

\*\* FOREIGN APPLICATIONS \*\*\*\*\*  
 REPUBLIC OF KOREA 2003-16300 03/15/2003 *pb*

IF REQUIRED, FOREIGN FILING LICENSE GRANTED  
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Foreign Priority claimed 35 USC 119 (a-d) conditions met Verified and Acknowledged	<input checked="" type="checkbox"/> yes <input type="checkbox"/> no <input checked="" type="checkbox"/> yes <input type="checkbox"/> no <input type="checkbox"/> Met after Allowance Examiner's Signature <i>[Signature]</i> Initials	STATE OR COUNTRY KOREA, REPUBLIC OF	SHEETS DRAWING 10	TOTAL CLAIMS 14	INDEPENDENT CLAIMS 2
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TITLE  
 Semiconductor tester coupling arrangement and electrical testing method thereof

<input type="checkbox"/> All Fees
<input type="checkbox"/> 1.16 Fees ( Filing )